

The *HILEVEL* Griffin III is a breakthrough in performance, precision, and reliability. Up to 512 logic pins, 64M vector depth and capture depth, all new high-accuracy DC parametrics, and optional mixed signal instrumentation in a multi-site system. Powerful Test System for Production, Engineering, Failure Analysis

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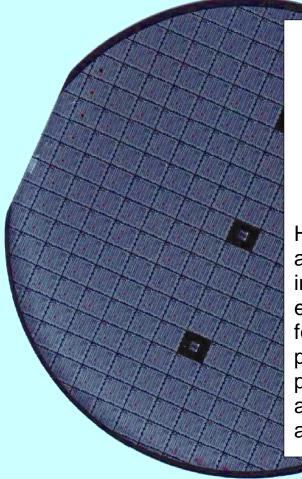




Price and Performance

The **Griffin III** system brings new price/performance efficiency to the Testerin-a-Head tradition, a concept created and introduced by *HILEVEL* in 1987. This tester is a superior solution for Mass Production, Engineering, and Failure Analysis test applications. With all new high-accuracy DC Parametrics, and capture memory of 64M to match the vector memory, this system takes the lead in the Price/Performance marathon.







HILEVEL¢ Symphony III software takes advantage of the ability to integrate external instruments into the **Griffin III** test flow, easily and efficiently. Rich in GUI functions for engineering and FA, plus all of the C++ programming capabilities that make a mass production tester fast. Symphony¢ built-in analysis tools make characterization fast and easy.



Specifications

TEST RATE

Max Data & Compare Rate: 200 MHz Max Cycle Rate:100 MHz, all modes (Two compares per cycle; two level transitions per cycle) Resolution: 125 KHz/1 MHz Accuracy: 0.1% of programmed value Minimum test rate: 125 KHz TIMING Timing Generators: 32, Globally Assigned Time Sets on the fly: 16 programmable timing/format sets on the fly (switched dynamically during test) 128 timing sets total Entire clock cycle + 10ns Range: **Resolution:** 50ps EPA (Edge Placement Accuracy): Standard Calibration: ± 1.5 ns Precision Calibration: ±500ps

PROGRAMMABLE PATTERN GENERATOR

Program Commands: Jump, Conditional Jump, Call, Conditional Call (four levels of Nesting), Return, Conditional Return, Loop (Repeat), Page (16 bit pages), Set Counter Value, Decrement Counter, Clear Fail Status, Trace mask On / Off, Pattern Match function.

DATA FORMATS

- NRZ Non-return to zero
- R0 Return to zero
- R1 Return to one
- RI Return to inhibit
- RC Return to compliment (Surround by compliment)

PIN ELECTRONICS (32 PE channels per slot)

Logic Pins: DRIVERS

All pins Input or Output or Bi-directional Min/Max Channels: 32/512 Increments of: 32 Pin To Pin Skew: +/- 500ps VIH: (VIL + 100 mV) to +6.5V VIL: -1.5V to (VIH ó 100mV) Resolution: 5mV Rails: 1 pair per pin Accuracy: +/- 10mV Sink/Source Current: 50mA/50mA Slew Rate: 1.5V/ns Capacitance: (Lumped + Continuous) <50pF Logic Pins: RECEIVERS/COMPARATORS Range: -1.5V to +6.5 Resolution: 5mV Rails: 1 per pin/per threshold Accuracy: +/- 15mV

PE Memory:
Vector Depth: 64M per pin
Acquisition Depth: 64M in Sequential mode 16M in Programmed mode
Scan (Optional):
Scan depth: Up to 8Gbit
Up to 128 scan chains
Full scan capture capability up to 64M.





Specifications

FCB: HIGH-SPEED CLOCKS

Eight fast clocks per FCB board with complementary outputs, up to 500MHz with programmable fractional ratio to the test rate (from 1:1 up to 8:1, in 0.5 steps). One FCB per system maximum.

WORKSTATION AND SOFTWARE

OS: Windows Automation: ACT (Automation C Tools), TexTest for ASCII test control, or HILEVEL AutoTest (GUI) Controller: PC workstation, Windows, and HILEVEL Symphony III software Interface: USB 3

DC PARAMETRIC MEASUREMENTS

One DCPMU per 32 pins (PE cards) Force Voltage Range: -8V to +8V Resolution: 1mV Force Current Range: -150 mA to +150 mA Resolution & Accuracy: Range Dependent

Voltage Measurement Range: -8V to +8VAccuracy: $0.2\% \pm 2mV$ Current Measurement Range: ± 150 mA Resolution & Accuracy: Range Dependent

Current Ranges	Resolution	Accuracy
± 200 nA	10 pA	$\pm 0.4\%$ of Value + 40 pA
$\pm 2 \mu A$	100 pA	$\pm 0.3\%$ of Value + 400 pA
$\pm 20 \ \mu A$	1 nA	$\pm 0.2\%$ of Value + 4 nA
$\pm 200 \mu A$	10 nA	$\pm 0.2\%$ of Value + 40 nA
$\pm 2 \text{ mA}$	100 nA	$\pm 0.2\%$ of Value + 400 nA
$\pm 20 \text{ mA}$	1 μΑ	$\pm 0.3\%$ of Value + 4 μ A
± 150 mA	10 μA	$\pm 0.4\%$ of Value + 40 μA

ENVIRONMENTAL	OTHER FEATURES
Power	Real time Failure Counter
220VAC single phase, Max 20A	Shows number of fails while running
Max Weight	
49kg (107 lbs) 512 pins installed	Display Capture Fails Only
Chassis only: 75 lbs, Each PEB: 2lbs	Acquisition Memory Compression
Dimensions (Test head only)	
H508mm x W438mm x D438mm	High-speed Acquisition Search:
Cooling	Search 64M of capture in <3 sec.
9 fans	
Temperature	Full õNext Cycleö Operation
60 to 80 °F (16 to 27°C)	Data Valid for the full next cycle



DUT POWER SUPPLIES

Main Internal Supplies PS1

Range: 0 to 8V, 0 to 2A Resolution: 10mV, 5mA Accuracy: +/-15mV

Multi-Site Supplies

One Supply per Pin Electronics Board (site) Voltage Range: 0-8V Resolution: 10mV Accuracy: 10mV Current Range: 0-1A Resolution: 10mA Accuracy: see table below

PS2 & PS3

Resolution: 5mV, 5mA

Accuracy: +/-15mV

Range: +/-16V, 0 to 1A

PS4

Range: 0 to 3.7V, 0 to 4A Resolution: 5mV, 5mA Accuracy: +/-10mV

PS per PE 0 to 8V, 1A per PE card/ 16 max.

Current Measurement Resolution

Range dependent. Best resolution is 1 nA.

DUT SUPPLY MEASUREMENT RANGES

One Measurement Unit per system

Voltage Measurement Range: -16V to +16V, Resolution: 5mV, Accuracy: $0.2\% \pm 2mV$

Current Ranges	Resolution	Accuracy
± 200 nA	10 pA	$\pm 0.5\%$ of Value + 100 pA
$\pm 2 \mu A$	100 pA	$\pm 0.4\%$ of Value + 500 pA
$\pm 20 \ \mu A$	1 nA	$\pm 0.2\%$ of Value + 4 nA
$\pm 200 \ \mu A$	10 nA	$\pm 0.2\%$ of Value + 40 nA
$\pm 2 \text{ mA}$	100 nA	$\pm 0.2\%$ of Value + 400 nA
$\pm 20 \text{ mA}$	1 μA	$\pm 0.4\%$ of Value + 4 μ A
± 200 mA	10 μA	$\pm 0.4\%$ of Value + 40 μ A
±2 A	100 µA	$\pm 0.5\%$ of Value + 400 μ A
± 5 A	250 µA	$\pm 0.5\%$ of Value + 1 mA





Excellence in test since 1979



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